



IECQ QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.:	IECQ-L ULTW 16.0003-13	Issue No.:	2	Status:	Current
Additional Site to Certification: IECQ-L ULTW 16.0003		Originally Issued: 2016/07/28			
Supersedes:	IECQ-L ULTW 16.0003-13 Issue 1	Issue Date:	2024/08/07	Site Added:	2023/08/15
CB Reference No.:	50600530 ITL	Expiration:	2025/07/27		

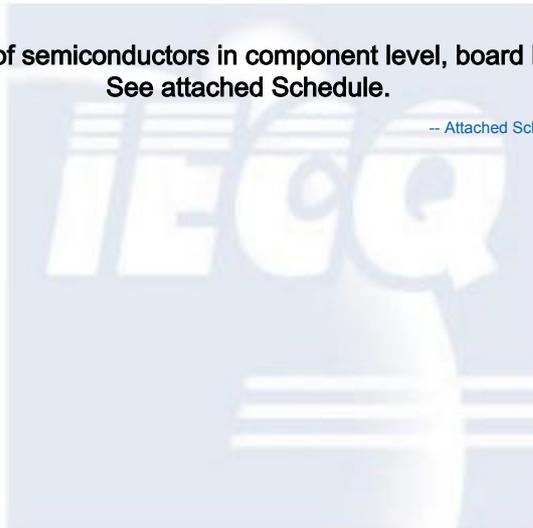
Materials Analysis Technology (Shanghai) Ltd.
 1F-2F, No. 100, Guiqiao Road, Pudong New District,
 Shanghai, P.R.C., 201206
 China

The organization, facilities and procedures have been assessed by the IECQ Certification Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of ISO/IEC 17025:2017 for the testing of component product under the IECQ.

Scope:

The reliability testing of semiconductors in component level, board level, system level.
 See attached Schedule.

-- Attached Schedule: IECQ-L_ULTW_50600530 ITL_08-07-24.pdf --



Approved by Certification Body (CB): DQS Group - DQS Taiwan Inc.

8F, 23, Yuan Huan West Road,
 Feng Yuan Dist., Taichung City
 Taiwan

Authorized person:
Bob CHEN



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.
 This Certificate of Conformity may be suspended or withdrawn in accordance with the Rules of Procedure of the IECQ System and its Schemes.
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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-13

CB Certificate No.: 50600530 ITL

Schedule Number: IECQ-L ULTW 16.0003-13-S Rev No.: 2 Revision Date: 2024/08/07 Page 1 of 2

Appendix-1 (50600530 ITL) Schedule of Scope to Certificate of Approval

Tests	Standards/Procedures
Scanning Acoustic Tomography (SAT)	T-EFA-3
Optical Microscope (OM)	T-OMI-3
High Temperature Operation Life test (HTOL)	IEC 60068-2-1, JESD22-A108
Low Temperature Operation Life test (LTOL)	IEC 60068-2-1, JESD22-A108
Bias Life test (BLT)	JESD22-A108
Temperature Cycling test (TCT)	JESD22-A104
Temperature variation test (TCC)	IEC 60068-2-14/33
Thermal Shock test (TST)	JESD22-A106
High Temperature Storage test (HTST)	IEC 60068-2-2, JESD22-A103
Low Temperature Storage test (LTST)	IEC 60068-2-1, JESD22-A119
Pressure Cooker test (PCT/UB-HAST)	JESD22-A102, JESD22-A118
Highly Accelerated Stress test (HAST)	JESD22-A110
Temperature and Humidity Storage test (THST)	IEC 60068-2-3, JEDEC22 A101
Temperature and Humidity with Bias test (THB)	JEDEC22 A101
High Temperature Reverse Bias test (HTRB)	JESD22-A108
High Temperature Gate Bias test (HTGB)	JESD22-A108

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DQS-Group - DQS Taiwan Inc., Feng Yuan Dist., Taichung City, Taiwan





IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

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High Humidity High Temperature Reverse Bias test (H3TRB)	JESD22-A101
Intermittent Operational Life test (IOL)	MIL-STD-750 Method 1037
Pre-conditioning test	JESD22-A113
Reflow test	J-STD-020
Solderability test	J-STD-002
Surface Mount Technology (SMT)	IPC-A-610, IPC-A-600
Drop test	ISTA 2A, IEC 60068-2-32
Vibration test and Shock Test	IEC 60068-2-6/27/29/34/64
Electro-migration test	IPC TM650 2.6.25
Conductive resistance test	IPC 9701
Power Cycling	AQG324
Power and Temperature Cycling(PTC)	JESD22-A105
Low Temperature Reverse Bias test(LTRB)	JESD22-A108

Technical Reviewer of DQS: Paul Yang Date: 8/7/2024

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